

IFW

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Toshio MATSUMOTO et al.

Group Art Unit : Not Yet Assigned

Appl. No. : 10/577,426

(National Stage of PCT/JP2004/015941)

Examiner : Not Yet Assigned

I.A. Filed : October 27, 2004

Confirmation No. : 4734

For : POROUS CALCIUM PHOSPHATE CERAMIC AND METHOD FOR  
PRODUCING THE SAME

## INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
U.S. Patent and Trademark Office  
Customer Service Window, Mail Stop AMENDMENT  
Randolph Building  
401 Dulany Street  
Alexandria, VA 22314

Sir:

In accordance with the duty of disclosure under 37 C.F.R. §§ 1.56, 1.97, and 1.98, Applicant hereby brings the following information to the attention of the Examiner, which includes information cited and discussed in the specification, the International Search Report, and the International Preliminary Examination Report issued in connection with counterpart International Application No. PCT/JP2004/015941. Copies of the International Search Report (in English and Japanese), and the International Preliminary Examination Report (in Japanese) were enclosed with the papers when entering the National Stage on April 27,

2006. The Examiner is invited to review these materials to inspect the relevance indicated during international examination with respect to the documents cited therein.

The Examiner is accordingly requested to consider each of these documents, and to make them of record in this application by initialing in the appropriate spaces on the attached Form-1449. Applicant respectfully requests that the Examiner include a copy of the initialed Form PTO-1449 with the next communication from the U.S. Patent and Trademark Office. If the Examiner needs additional copies of any of the documents, the Examiner is requested to contact the undersigned. For the Examiner's convenience, the documents are listed below.

- (1) Japanese Laid-Open Patent Publication No. HEI 03-065579, together with an English language Abstract, and certified English language translation thereof;
- (2) Japanese Laid-Open Patent Publication No. 2003-073182, together with an English language Abstract and English language machine translation thereof;
- (3) U.S. Patent Application Publication No. 2004/0153165 to LI et al., which published on August 5, 2004. Applicants note that this document was apparently improperly cited as US 2003/355827 in the International Search Report. Applicants note that U.S. Pat. App. Pub.

No. 2004/0153165 corresponds to U.S. Application No. 10/355,827, and further, there is no U.S. Patent Application Publication 2003/355827;

- (4) International Patent Application Publication No. WO 01/54747, along with family member U.S. Patent Application Publication No. 2003/0152606 to GERBER, which published on August 14, 2003;
- (5) Japanese Patent No. 2597355;
- (6) Japanese Laid-Open Patent Publication No. 2000-302567, along with family member U.S. Patent No. 6,340,648 to IMURA et al., which issued on January 22, 2002. Applicants note that this document is also cited on pages 1 and 2 of the specification of the above-captioned application; and
- (7) Japanese Laid-Open Patent Publication No. 2002-179478, along with family member U.S. Patent Application Publication No. 2002/0114938 to MATSUMOTO, which published on August 22, 2002. Applicants note that the Japanese document is cited on page 9 of the specification of the above-captioned application.

The relevance of the documents cited in the International Search Report, as ascertained by the International Examiner, are set forth in the International Search Report.

Applicants further submit the following documents:

- (8) U.S. Patent Application Publication No. 2004/0185181 to MATSUMOTO, which published on September 23, 2004;
- (9) U.S. Patent Application Publication No. 2005/0119761 to MATSUMOTO, which published on June 2, 2005.

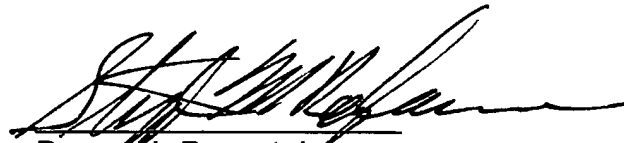
Further to 37 C.F.R. §1.98 (a)(2)(ii), copies of the U.S. patent and patent application publications are not enclosed herewith. However, if any copy is needed, the Examiner is respectfully requested to contact the undersigned.

Applicants respectfully request that the Examiner consider the above material and cite the same. Copies of the above-noted foreign documents, including the noted English language Abstracts and translations, are attached hereto, and all of the documents are listed on an attached PTO-1449 Form. The Examiner is requested to initial the appropriate spaces on the attached Form and to return a copy of the completed Form to Applicants with the next official communication in the present application.

Applicant notes that an Office Action on the merits has not issued in the present application, and thus no fee is believed necessary to ensure consideration of the submitted material.

Should the Examiner have any questions, the Examiner is invited to  
contact the undersigned at the below-listed telephone number.

Respectfully submitted,  
Akira YUFUKU et al.



Bruce H. Bernstein  
Reg. No. 29,027

Stephen M. Roylance  
Reg. No. 31,296

July 28, 2006  
GREENBLUM & BERNSTEIN, P.L.C.  
1950 Roland Clarke Place  
Reston, Virginia 20191  
(703) 716-1191

{P29832 00032951.DOC}

U.S. Department of Commerce  
Patent and Trademark Office

Atty. Docket  
P29832

Application No.  
10/577,426

**INFORMATION DISCLOSURE STATEMENT**  
**BY APPLICANT**  
(Use several sheets if necessary)

(Use several sheets if necessary)

Applicant  
Toshio MATSUMOTO et al.

Filing Date  
I.A. Filed October 27, 2004

Group	Not Yet Assigned
-------	------------------

U.S. PATENT OFFICE  
JUL 28 2006  
PATENT & TRADEMARK OFFICE

U.S. PATENT DOCUMENTS

[illegible]

## FOREIGN PATENT DOCUMENTS

[illegible]

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

	1	English Language Abstract of JP 3-065579.
	2	English Language Abstract of JP 2003-073182.

EXAMINER

DATE CONSIDERED

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.